Instrument title:	**NT-MDT Stand Alone "SMENA" Scanning Probe Microscope**
Photo:	
Technical details:	**Measuring modes:** **In air:** Contact AFM/ LFM/ ResonantMode AFM (semicontact + noncontact)/ Phase Imaging/ Force Modulation (viscoelastisity)/ Adhesion Force Imaging/ Spreading Resistance Imaging/ SCM/ SKM/ MFM/ EFM/ AFM, Voltage, RM Lithographies
Application example:	Optical and Magnetic Storage, Coating and Polishing Quality Control, Large Optics, Polymers, Biology and Medicine, Semiconductors, Materials Science and many others.
Responsible: **(name, second name, e-mail)**	Aleksejs Kuzmins (a.kuzmin@cfi.lu.lv)

Technical specification

Sample Size	Unlimited *Note: Small samples (up to 100x100x20mm) can be placed between the SMENA head legs.*
Scanner	50x50x2.5µm
Min. Scanning Step	0.006nm; 0.012nm
Scan Type	By Probe
Sample positioning range	5x5mm
Positioning resolution	5µm
Optical viewing system	Numerical aperture 0.1 Magnification 58x to 578x Horizontal field of view 2 to 0,51mm
Control System	SPM Controller